

---

---

**Optics and photonics — Lasers  
and laser-related equipment —  
Cavity ring-down method for high-  
reflectance and high-transmittance  
measurements**

*Optique et photonique — Lasers et équipement associé aux lasers —  
Méthode d'alternance de la cavité pour les mesurages du facteur de  
réflexion et du facteur de transmission*

iTeh STANDARD PREVIEW  
(standards.iteh.ai)

[ISO 13142:2021](https://standards.iteh.ai/catalog/standards/sist/ce11fda4-c182-431a-8ba9-07c90748d6aa/iso-13142-2021)

<https://standards.iteh.ai/catalog/standards/sist/ce11fda4-c182-431a-8ba9-07c90748d6aa/iso-13142-2021>



## iTeh STANDARD PREVIEW (standards.iteh.ai)

ISO 13142:2021

<https://standards.iteh.ai/catalog/standards/sist/ce11fda4-c182-431a-8ba9-07c90748d6aa/iso-13142-2021>



### **COPYRIGHT PROTECTED DOCUMENT**

© ISO 2021

All rights reserved. Unless otherwise specified, or required in the context of its implementation, no part of this publication may be reproduced or utilized otherwise in any form or by any means, electronic or mechanical, including photocopying, or posting on the internet or an intranet, without prior written permission. Permission can be requested from either ISO at the address below or ISO's member body in the country of the requester.

ISO copyright office  
CP 401 • Ch. de Blandonnet 8  
CH-1214 Vernier, Geneva  
Phone: +41 22 749 01 11  
Email: [copyright@iso.org](mailto:copyright@iso.org)  
Website: [www.iso.org](http://www.iso.org)

Published in Switzerland

# Contents

Page

|   |           |
|---|-----------|
| <b>Foreword</b> .....   | <b>iv</b> |
| <b>Introduction</b> .....   | <b>v</b>  |
| <b>1 Scope</b> .....  | <b>1</b>  |
| <b>2 Normative references</b> .....   | <b>1</b>  |
| <b>3 Terms and definitions</b> .....  | <b>1</b>  |
| <b>4 Symbols used and units of measure</b> .....  | <b>2</b>  |
| <b>5 Test principles</b> .....  | <b>2</b>  |
| 5.1 General.....  | 2         |
| 5.2 Decay time of initial cavity and reflectance of cavity mirrors.....                       | 2         |
| 5.3 Decay time of test cavity and reflectance/transmittance of test sample.....               | 4         |
| 5.4 High reflectance/transmittance measurement with an optical feedback CRD technique ...     | 5         |
| <b>6 Preparation of test sample and measurement arrangement</b> .....                         | <b>6</b>  |
| 6.1 Test sample.....  | 6         |
| 6.2 Laser source.....   | 6         |
| 6.3 Ring-down cavity.....   | 7         |
| 6.4 Detection unit.....   | 7         |
| 6.5 Data acquisition and processing.....  | 7         |
| 6.6 Environment.....  | 8         |
| <b>7 Test procedure</b> .....   | <b>8</b>  |
| 7.1 General.....  | 8         |
| 7.2 Measurement of decay time of initial cavity.....  | 8         |
| 7.3 Calculation of reflectance of cavity mirrors.....   | 9         |
| 7.4 Measurement of decay time of test cavity.....   | 9         |
| 7.5 Calculation of reflectance/transmittance of test sample.....                              | 9         |
| 7.6 Assessments of the measurement.....   | 9         |
| <b>8 Main error factors</b> .....   | <b>10</b> |
| 8.1 Influence of the instrumental response time on reflectance/transmittance measurement..... | 10        |
| 8.1.1 General.....  | 10        |
| 8.1.2 Multi-parameter fitting method.....   | 10        |
| 8.1.3 Data truncation method.....   | 11        |
| 8.2 Measurement error of the reflectance of cavity mirrors.....                               | 11        |
| 8.3 Measurement error of the reflectance/transmittance of test sample.....                    | 12        |
| <b>9 Test report</b> .....  | <b>12</b> |
| <b>Annex A (informative) Reflectance/transmittance reliability check experiment</b> .....     | <b>14</b> |
| <b>Annex B (informative) Test report</b> .....  | <b>15</b> |
| <b>Bibliography</b> .....   | <b>17</b> |

## Foreword

ISO (the International Organization for Standardization) is a worldwide federation of national standards bodies (ISO member bodies). The work of preparing International Standards is normally carried out through ISO technical committees. Each member body interested in a subject for which a technical committee has been established has the right to be represented on that committee. International organizations, governmental and non-governmental, in liaison with ISO, also take part in the work. ISO collaborates closely with the International Electrotechnical Commission (IEC) on all matters of electrotechnical standardization.

The procedures used to develop this document and those intended for its further maintenance are described in the ISO/IEC Directives, Part 1. In particular the different approval criteria needed for the different types of ISO documents should be noted. This document was drafted in accordance with the editorial rules of the ISO/IEC Directives, Part 2 (see [www.iso.org/directives](http://www.iso.org/directives)).

Attention is drawn to the possibility that some of the elements of this document may be the subject of patent rights. ISO shall not be held responsible for identifying any or all such patent rights. Details of any patent rights identified during the development of the document will be in the Introduction and/or on the ISO list of patent declarations received (see [www.iso.org/patents](http://www.iso.org/patents)).

Any trade name used in this document is information given for the convenience of users and does not constitute an endorsement.

For an explanation on the voluntary nature of standards, the meaning of ISO specific terms and expressions related to conformity assessment, as well as information about ISO's adherence to the World Trade Organization (WTO) principles in the Technical Barriers to Trade (TBT) see the following URL: [www.iso.org/iso/foreword.html](http://www.iso.org/iso/foreword.html). (standards.iteh.ai)

This document was prepared by ISO/TC 172, *Optics and photonics*, Subcommittee SC 9, *Lasers and electro-optical systems*.  
ISO 13142:2021

<https://standards.iteh.ai/catalog/standards/sist/c11fda4-c182-431a-8ba9-7997486d1102>

This second edition cancels and replaces the first edition ISO 13142:2015, which has been technically revised.

The main changes compared to the previous edition are as follows:

- addition of transmittance measurements into the document.

Any feedback or questions on this document should be directed to the user's national standards body. A complete listing of these bodies can be found at [www.iso.org/members.html](http://www.iso.org/members.html).

## Introduction

With the development of film-deposition technology, the performance of optical thin films, especially the highly reflective (HR) and highly anti-reflective (AR) coatings which are widely used in large high-power laser systems, interferometric gravitational-wave detectors, laser gyroscopes, and cavity-enhanced and cavity ring-down spectroscopy applications, has been substantially improved in recent years. Laser-based optical systems require some optical components with extremely high reflectance or transmittance characteristic. It is necessary to be able to measure this reflectance or transmittance characteristic precisely. Up to now, the ISO standardized testing methods for reflectance/transmittance of optical laser components have the accuracy limit of approximately 0,01 % (for measurement of absolute reflectance/transmittance), which are not appropriate for measuring the reflectance /transmittance higher than 99,99 %, or in some cases measurement accuracy better than 0,01 % is required. The measurement procedures in this document have been optimized to allow the measurement of high reflectance or transmittance (larger than 99 %, theoretically up to 100 %) of optical laser components using the cavity ring-down technique which provides reflectance or transmittance data with high accuracy, high repeatability and reproducibility, and high reliability.

## iTeh STANDARD PREVIEW (standards.iteh.ai)

ISO 13142:2021

<https://standards.iteh.ai/catalog/standards/sist/ce11fda4-c182-431a-8ba9-07c90748d6aa/iso-13142-2021>

**iTeh STANDARD PREVIEW**  
**(standards.iteh.ai)**

ISO 13142:2021

<https://standards.iteh.ai/catalog/standards/sist/ce11fda4-c182-431a-8ba9-07c90748d6aa/iso-13142-2021>

# Optics and photonics — Lasers and laser-related equipment — Cavity ring-down method for high-reflectance and high-transmittance measurements

## 1 Scope

This document specifies measurement procedures for the precise determination of the high reflectance or high transmittance (>99 %) of optical laser components.

The methods given in this document are intended to be used for the testing and characterization of high reflectance of both concave and plane mirrors or high transmittance of plane windows used in laser systems and laser-based instruments. The reflectance of convex mirrors or transmittance of positive or negative lenses can also be tested by taking into consideration the radius of curvature of the mirror surface or the focal length of the lens. This document is complementary to ISO 15368 which specifies the measurement procedures for the determination of reflectance and transmittance of optical components with spectrophotometry. ISO 15368 is applicable to the measurements of reflectance and transmittance in the range from 0 % to 100 % with a typical accuracy of  $\pm 0,3$  %, and is therefore not applicable to the precise measurements of reflectance and transmittance higher than 99,9 %.

## 2 Normative references

The following documents are referred to in the text in such a way that some or all of their content constitutes requirements of this document. For dated references, only the edition cited applies. For undated references, the latest edition of the referenced document (including any amendments) applies.

ISO 11145, *Optics and photonics — Lasers and laser-related equipment — Vocabulary and symbols*

ISO 14644-1, *Cleanrooms and associated controlled environments — Part 1: Classification of air cleanliness by particle concentration*

ISO 80000-7, *Quantities and units — Part 7: Light and radiation*

## 3 Terms and definitions

For the purposes of this document, the terms and definitions given in ISO 11145 and ISO 80000-7 and the following apply.

ISO and IEC maintain terminological databases for use in standardization at the following addresses:

— ISO Online browsing platform: available at <https://www.iso.org/obp>

— IEC Electropedia: available at <http://www.electropedia.org/>

### 3.1

#### reflectance

<for incident radiation of given wavelength, polarization and angle of incidence> ratio of the reflected radiant or luminous flux to the incident flux in the given conditions

### 3.2

#### transmittance

<for incident radiation of given wavelength, polarization and angle of incidence> ratio of the transmitted radiant or luminous flux to the incident flux in the given conditions

## 4 Symbols used and units of measure

Table 1 — Symbols used and units of measure

| Symbol               | Term   | Unit            |
|----------------------|--|-----------------|
| $c$                  | speed of light in measurement environment  | m/s             |
| $c_0$                | speed of light in vacuum   | m/s             |
| $h(t)$               | impulse response of the ring-down cavity   |                 |
| $h_0(t)$             | Instrumental response function   |                 |
| $L_0$                | length of the initial cavity   | m               |
| $L$                  | length of the test cavity  | m               |
| $\Delta L_0$         | measurement error of the initial cavity length   | m               |
| $\Delta L$           | measurement error of the test cavity length  | m               |
| $n$                  | refractive index of air in measurement environment   |                 |
| $R$                  | average reflectance of the concave cavity mirrors, equals square root of $R_1 \times R_2$                                |                 |
| $R_s$                | reflectance of the test sample   |                 |
| $T_s$                | transmittance of the test sample   |                 |
| $R_1, R_2$           | reflectance of two concave cavity mirrors  |                 |
| $R_3$                | reflectance of the planar cavity mirror  |                 |
| $\tau_{\text{inst}}$ | instrumental response time   | s               |
| $t$                  | time   | s               |
| $u(t)$               | negative-step function   |                 |
| $\alpha$             | the overall optical loss coefficient (absorption plus scattering) of the gases inside the cavity at the laser wavelength | $\text{m}^{-1}$ |
| $n_s$                | refractive index of the transmissive test sample substrate   |                 |
| $d$                  | thickness of the transmissive test sample or central thickness of a lens to be tested                                    | m               |
| $\delta(t)$          | delta function   |                 |
| $\theta$             | angle of incidence of the test sample  | rad             |
| $\rho$               | radius of curvature of concave surface of the cavity mirror  | m               |
| $\tau_0$             | decay time of the initial cavity   | s               |
| $\tau$               | decay time of the test cavity  | s               |
| $\Delta\tau_0$       | measurement error of the decay time of the initial cavity  | s               |
| $\Delta\tau$         | measurement error of the decay time of the test cavity   | s               |

## 5 Test principles

### 5.1 General

The conventional reflectance/transmittance measurement techniques (spectrophotometry and laser radiometry) are based on measuring the relative changes of light power reflected/transmitted by the test sample. The measurement accuracy is limited by the power fluctuations of the light sources. The cavity ring-down (CRD) technique, on the other hand, is based on the measurement of the decay rate of laser power trapped in a ring-down cavity consisting of at least two highly reflective mirrors. It is therefore totally immune to the power fluctuations of the light sources. The CRD technique can achieve a measurement accuracy that far exceeds the limit set by the power fluctuations of the light sources.

### 5.2 Decay time of initial cavity and reflectance of cavity mirrors

When a laser beam is coupled into the ring-down cavity, it will gradually leak out of the cavity as a small fraction of the light is transmitted through the cavity mirrors at each reflection. The temporal



behaviour of the cavity output signal immediately after the laser pulse (in the pulsed case, as shown in [Figure 1](#)) or immediately after the laser power is switched off [in the continuous wave (cw) case, as shown in [Figure 2](#), or at the falling edge of a square-wave modulated power] can be expressed as an exponentially decay function of time according to the following decay route given in [Formula \(1\)](#):

$$I(t) \propto I_0 \exp\left(\frac{-t}{\tau_0}\right) \tag{1}$$

Where  $I_0$  is the initial light intensity of the cavity output signal,  $\tau_0$  can be expressed as given in [Formula \(2\)](#):

$$\tau_0 = \frac{L_0}{c(\alpha L_0 - \ln \sqrt{R_1 R_2})} \tag{2}$$

With [Formula \(3\)](#):

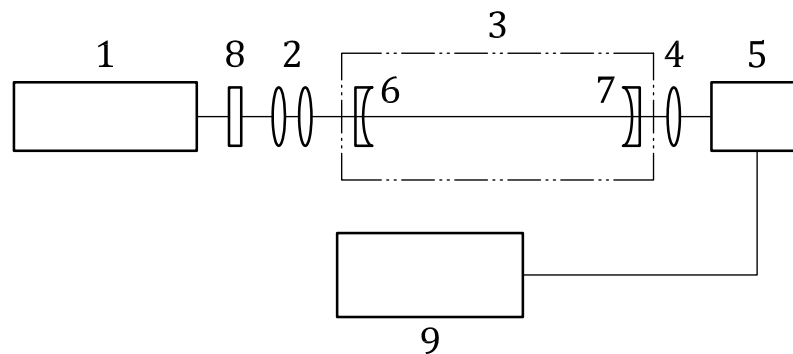
$$c = \frac{c_0}{n} \tag{3}$$

For the case where at test laser wavelength the absorptance and scattering loss of gases inside the ring-down cavity are negligible, the empty cavity ring-down time,  $\tau_0$ , is only dependent upon the cavity length and the reflectance of the cavity mirrors and [Formula \(2\)](#) reduces to [Formula \(4\)](#):

$$\tau_0 = \frac{-L_0}{c \ln \sqrt{R_1 R_2}} \tag{4}$$

By experimentally measuring the decay time,  $\tau_0$ , the average reflectance of the cavity mirrors can be calculated as [Formula \(5\)](#):

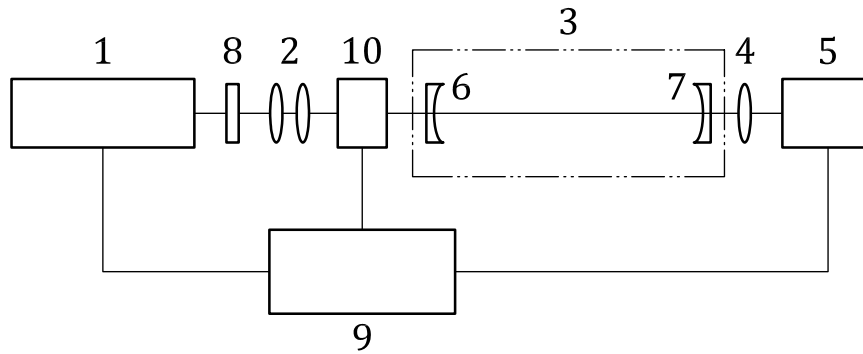
$$R = \sqrt{R_1 R_2} = \exp\left(\frac{-L_0}{c\tau_0}\right) \tag{5}$$



**Key**

- |   |                      |   |   |
|---|----------------------|---|---|
| 1 | laser                | 6 | input cavity mirror, concave high reflectance mirror  |
| 2 | mode matching optics | 7 | output cavity mirror, concave high reflectance mirror |
| 3 | initial cavity       | 8 | polarizer   |
| 4 | focusing lens        | 9 | control and data-processing unit                      |
| 5 | photo-detector       |   |   |

**Figure 1 — Schematic of optical arrangement for pulsed-CRD technique for high reflectance measurement**



**Key**

- |   |                      |    |   |
|---|----------------------|----|---|
| 1 | laser                | 6  | input cavity mirror, concave high reflectance mirror  |
| 2 | mode matching optics | 7  | output cavity mirror, concave high reflectance mirror |
| 3 | initial cavity       | 8  | polarizer   |
| 4 | focusing lens        | 9  | control and data-processing unit                      |
| 5 | photo-detector       | 10 | optical switch  |

**Figure 2 — Schematic of optical arrangement for cw-CRD technique for high reflectance measurement**

iTeh STANDARD PREVIEW  
(standards.iteh.ai)

**5.3 Decay time of test cavity and reflectance/transmittance of test sample**

If a reflective/transmissive planar test sample or a lens is to be measured, a test ring-down cavity is formed by inserting this reflective/transmissive test sample or lens into the initial cavity as shown in [Figure 3](#) (for reflective sample) or [Figure 4](#) (for transmissive sample or lens). The incident angle of the laser beam on the test sample follows the required incident angle of the test sample. In case of a lens, the laser beam should propagate through the centre of the lens. In this case, the decay time of the test cavity can be expressed as [Formula \(6\)](#):

$$\tau = \frac{-L}{c \ln(R_s \cdot \sqrt{R_1 R_2})} \tag{6}$$

for the reflective sample, and as [Formula \(7\)](#):

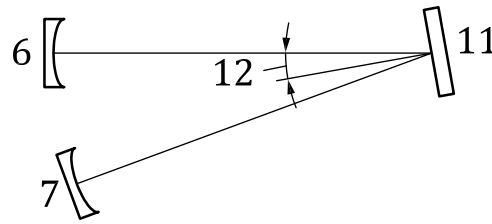
$$\tau = \frac{-[L + (n_s - 1)d]}{c \ln(T_s \cdot \sqrt{R_1 R_2})} \tag{7}$$

for the transmissive sample or lens. Therefore, from [Formulae \(4\)](#) and [\(6\)](#), the reflectance,  $R_s$ , of the reflective test sample can be calculated as [Formula \(8\)](#):

$$R_s = \exp\left(\frac{L_0}{c\tau_0} - \frac{L}{c\tau}\right) \tag{8}$$

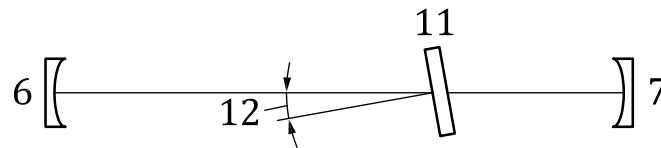
And, combining [Formulae \(4\)](#) and [\(7\)](#), the transmittance,  $T_s$ , of the transmissive test sample or lens can be calculated as [Formula \(9\)](#):

$$T_s = \exp\left[\frac{L_0}{c\tau_0} - \frac{L + (n_s - 1)d}{c\tau}\right] \tag{9}$$

**Key**

- 6 input cavity mirror, concave high reflectance mirror 11 reflective test sample  
7 output cavity mirror, concave high reflectance mirror 12 angle of incidence of test sample

**Figure 3 — Schematic of optical arrangement of test cavity for reflectance measurement**

**Key**

- 6 input cavity mirror, concave high reflectance mirror 11 transmissive test sample or lens  
7 output cavity mirror, concave high reflectance mirror 12 angle of incidence of test sample

**Figure 4 — Schematic of optical arrangement of test cavity for transmittance measurement**  
(standards.iteh.ai)

NOTE Reflectances of HR mirrors with 0° angle of incidence (AOI) are normally measured at AOI of 3° to 8°, which is considered sufficient. However, if required, the reflectance measurement at 0° AOI is possible. This can be done by pairing the test mirror and two cavity mirrors separately (that is, separate pairs of two cavity mirrors, of one cavity mirror and the test mirror, and of another cavity mirror and the test mirror) to form three stable straight cavities and measure three decay times for the three combinations, separately. From the three measured decay times the reflectance of the test mirror, as well as the reflectances of the two cavity mirrors can be determined via [Formula \(4\)](#), respectively.

#### 5.4 High reflectance/transmittance measurement with an optical feedback CRD technique

In the cw-CRD case, an optical feedback CRD (OF-CRD) scheme employing a semiconductor laser as the light source (shown in [Figure 5](#)) can be used for the reflectance/transmittance measurement with an improved signal-to-noise ratio in the CRD signals. In OF-CRD scheme, the initial cavity consists of three cavity mirrors – two concave mirrors and one planar mirror. The beam from the semiconductor laser is coaxially coupled into the ring-down cavity through the high-reflectance planar cavity mirror. The optical feedback (back-reflection of the laser beam) from the ring-down cavity is retro-reflected into the oscillator cavity of the semiconductor laser. Due to the self-mixing effect of the semiconductor laser, the spectral linewidth of the laser is significantly reduced by the frequency selected optical feedback, resulting in significant enhancement of the coupling efficiency of the laser power into the ring-down cavity and therefore a large increase of the CRD amplitude. When the laser power is modulated by a square wave signal, the cavity decay signal can be obtained at the falling edge of the square wave signal. The test principle is the same as that presented in [5.2](#) and [5.3](#). The item  $\sqrt{R_1 R_2}$  in [Formulae \(2\)](#) to [\(7\)](#) should be substituted by  $\sqrt{R_1 R_2} \cdot R_3$  in OF-CRD scheme.

The following two measurements are necessary to determine the reflectance/transmittance of the test sample:

- $\tau_0$  and  $L_0$  are measured with the initial cavity;
- $\tau$  and  $L$  are measured with the test cavity.